

Resource Summary Report

Generated by [RRID](#) on Aug 5, 2026

JEOL: JSM-IT200 InTouchScope Scanning Electron Microscope (SEM)

RRID:SCR_020186

Type: Tool

Proper Citation

JEOL: JSM-IT200 InTouchScope Scanning Electron Microscope (SEM)
(RRID:SCR_020186)

Resource Information

URL: <https://www.jeolusa.com/PRODUCTS/Scanning-Electron-Microscopes-SEM/HV-LV-Tungsten-LaB6-SEMs/JSM-IT200-InTouchScope>

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Description: Scanning electron microscope that is compact and versatile and delivers high resolution imaging with unsurpassed low kV performance and high sensitivity solid state BSE detector included with LV models.

Resource Type: instrument resource

Keywords: Jeol, JEOL, Scanning Electron Microscope, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: JEOL: JSM-IT200 InTouchScope Scanning Electron Microscope (SEM)

Resource ID: SCR_020186

Alternate IDs: Model_Number_JSM_IT200

Record Creation Time: 20220129T080349+0000

Record Last Update: 20260801T190641+0000

Ratings and Alerts

No rating or validation information has been found for JEOL: JSM-IT200 InTouchScope Scanning Electron Microscope (SEM).

No alerts have been found for JEOL: JSM-IT200 InTouchScope Scanning Electron Microscope (SEM).

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.